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WPC RF Exposure Report

Applicant Name: SAMSUNG Electronics Co., Ltd. 129, Samsung-ro, Yeongtong-gu, Suwon-Si, Gyeonggido, 16677 Rep. of Korea Date of Issue: May. 25, 2022 Test Report No.: HCT-SR-2205-FC001-R2 Test Site: HCT CO., LTD.

A3LSMG990U2 FCC ID: Mobile Phone Equipment Type: Application Type Certification FCC Part 1 SUBPART I FCC Rule Part(s): FCC Part 2 SUBPART J KDB 680106 D01 Model Name: SM-G990U2 Multi Model Name: SM-G990U3/DS Date of Test: May.11, 2022

This device has been shown to be capable of compliance for the above standars for uncontrolled environment/general population exposure limits specified in FCC KDB procedures and had been tested in accordance with the measurement procedures specified in FCC KDB procedures.

I attest to the accuracy of data. All measurements reported herein were performed by me or were made under my supervision and are correct to the best of my knowledge and belief. I assume full responsibility for the completeness of these measurements and vouch for the qualifications of all persons taking them.

Tested By

Jung Hun, Park Test Engineer SAR Team Certification Division

Reviewed By

Yun-jeang, Heo Technical Manager SAR Team Certification Division

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DOCUMENT HISTORY

Rev.	DATE	DESCRIPTION
0	May. 13, 2022	First Approval Report
1	May. 20, 2022	Revised Sec.3, 6
2	May. 25, 2022	Revised Sec. 3



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1. Test Methodology

The DUT was assessed in accordance with FCC KDB 680106 D01 RF Exposure Wireless Charging App v03r01.

2. Test Location.

2.1 Test Laboratory.

Company Name:	HCT Co., LTD
Address:	74, Seoicheon-ro 578beon-gil, Majang-myeon, Icheon-si, Gyeonggi-do, 17383, Rep. of Korea
Telephone:	+82 31 645 6300
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2.2 Test Facillities

Our laboratories are accredited and approved by the following approval agencies according to ISO/IEC 17025.

	National Radio Research Agency (Designation No. KR0032)
Korea:	KOLAS (Tesing No. KT197)



3. DEVICE UNDER TEST DESCRIPTION

Applicant Name:	SAMSUNG Electronics Co., Ltd.	
Model Name:	SM-G990U2	
Multi-Model Name:	SM-G990U3/DS	
EUT Type:	Mobile Phone	
Application Type:	Certification	

3.1 Description of DUT

The DUT is a mobile phone with a WPT (Wireless Power Transfer) feature using an inductive charging coil to charge a phone, watch or EarBuds. The charing frequency is between 110 kHz to 148 kHz, and the maximum transfer power consumption is 7.5 W in charging status.

SM-G990U2, SM-G990U3/DS were tested and the worst case results were reported. (Worst case : SM-G990U2)

3.2 TEST Configration

Description
Charging from Phone to DUT
Charging from Phone to DUT(TA Charging from DUT)
Charging from Phone to DUT
Charging from Phone to DUT(TA Charging from DUT)
Charging from Watch to DUT
Charging from Watch to DUT(TA Charging from DUT)
Charging from EarBuds to DUT
Charging from EarBuds to DUT(TA Charging from DUT)

Note :

1. Configuration 2,4,6 and 8 were tested with the worst case of configuration 1,3,5 and 7



3.3 KDB 680106 D01 v03 SECTION 5.b) EQUIPMENT APPROVAL CONSIDERATIONS

Requirement	Device	
(1) Power transfer frequency is less than 1 MHz.	Yes. Operation Frequency is between 110 kHz to 148 Khz.	
(2) Output power from each primary coil is less than or equal to 15 watts.	Yes. Maximum power is 7.5 Watts.	
(3) The transfer system includes only single primary and secondarty coils. This includes charging systems that may have multiple primary coils and client that are able to detect and allow coupling only between individual pairs of coils	Yes.	
(4) Client device is placed directly in contact with the transmitter.	Yes.	
(5) Mobile expousure conditions only(portable exposure conditions are not convered by this exclusion).	Yes.	
(6) The aggregate H-field strengths at 15 cm surrounding the device and 20 cm above the top surface from all simultaneous transmitting coils are demonstrated to be less than 50% of the MPE limit.	Yes. The aggregate field strengths at 20 cm from the device is 9.3 % and at 15cm from the device is 8.3% of the FCC H field limit.	



3.4 DESCRUPTION OF TEST SETUP SUPPORT EQUIPMENT & PERIPHERALS

SUPPORT EQUIPMENT & PERIPHERALS LIST						
Description	Manufacturer	Model	Serial Numver	FCC ID		
Watch	SAMSUNG Electronics Co., Ltd.	SM-R835F	RFAM80Q6NJW	A3LSMR835		
Phone SAMSUNG Electronics Co., Ltd.		SM-G986B/DS	RF8M70ZA4FH	A3LSMG986B		
EarBuds	SAMSUNG Electronics Co., Ltd.	SM-R180N-L	A2101112033	A3LSMR180L		
	SAMSUNG Electronics Co., Ltd.	SM-R180N-R	A2101112034	A3LSMR180R		

TEST SETUP

The following three modes are tested in test configuration;

All Position of client device were investigated and the worst position results are reported.

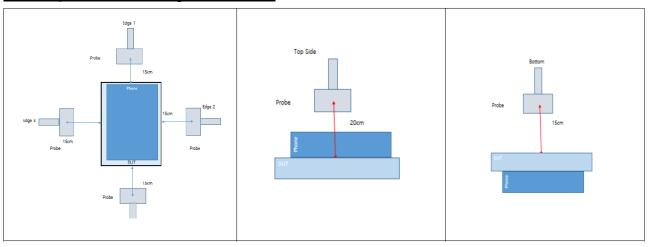
Mode				
Operating				
(SUPPORT Equipment, <10% Power Charging)				
Operating				
(SUPPORT Equipment, 50~55% Power Charging)				
Operating				
(SUPPORT Equipment, 90~95% Power Charging)				



MEASUREMENT TEST SETUP

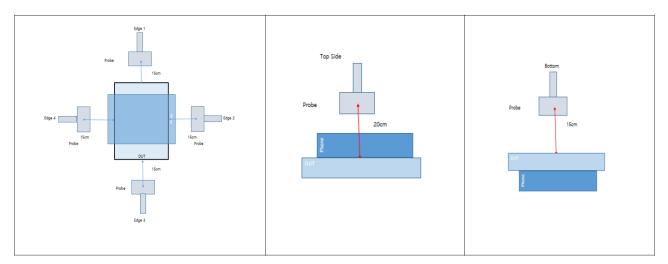
The measurement was taken using a probe place 15 cm from the edges of DUT or 20 cm above the DUT. Measurement were from the top and all sides of the DUT per KDB680106 D01 v03. Additionally, as the DUT to phone configuration could result with the DUT place either above or below the phone, measurements were performed 'below' th DUT by flipping the DUT/phone so that the DUT was uppermost.

The probe was moved along the edges or above the DUT to a position that showed the maximum field strength. This position was used for the reported result.

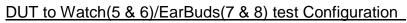


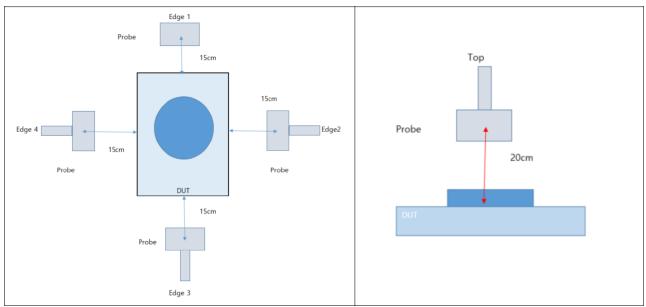
DUT to phone test Configuration 1 & 2

DUT to phone test Configuration 3 & 4









4. TEST AND MEASUREMENT EQUIPMENT

The following test and measurement equipment was used for the tests documented in this report :

Manufacturer	Model namr	Description	S/N	Calib. Date	Calib.Due
Narda	ELT-400	Exposure Level Tester	N-0538	11/05/2021	11/05/2022
Narda	ELT-3 cm ² Probe	Magnetic (B) field	C-0171	04/18/2022	04/18/2023

5. MAXIMUM PERMISSIBLE RE EXPOSURE

5.1 FCC RULES

1.13010 The criteria listed in Table 1 shall be used to evaluate the envirimental impact of human exposure to radio-frequency(RF) ragiation as specified in 1.1307(b), except in the case of portable devices which shall ge evaluated according th the provisions of 2.1093 of this chapter.

TABLE 1—LIMITS FOR MAXIMUM PERMISSIBLE EXPOSURE (MPE)

Frequency range (MHz)	Electric field strength (V/m)	Magnetic field strength (A/m)	Power density (mW/cm²)	Averaging time (minutes)			
(A) Limits for Occupational/Controlled Exposures							
0.3–3.0 3.0–30 30–300 300–1500 1500–100,000	614 1 <i>8</i> 42/f 61.4	1.63 4.89/f 0.163	*(100) *(900/f²) 1.0 f/300 5	6 6 6 6			
(B) Limits for General Population/Uncontrolled Exposure							
0.3–1.34 1.34–30	614 824 <i>/</i> f	1.63 2.19/f	*(100) *(180/f ²)	30 30			

TABLE 1-LIMITS FOR MAXIMUM PERMISSIBLE EXPOSURE (MPE)-Continued

Frequency range (MHz)	Electric field strength (V/m)	Magnetic field strength (A/m)	Power density (mW/cm²)	Averaging time (minutes)
30–300 300–1500 1500–100,000	27.5	0.073	0.2 f/1500 1.0	30 30 30

f = frequency in MHz

* = Plane-wave equivalent power density NOTE 1 TO TABLE 1: Occupational/controlled limits apply in situations in which persons are exposed as a consequence of their employment provided those persons are fully aware of the potential for exposure and can exercise control over their exposure. Limits for occupational/controlled exposure also apply in situations when an individual is transient through a location where occu-pational/controlled limits apply provided he or she is made aware of the potential for exposure. NOTE 2 TO TABLE 1: General population/uncontrolled exposures apply in situations in which the general public may be ex-posed, or in which persons that are exposed as a consequence of their employment may not be fully aware of the potential for exposure.

exposure or can not exercise control over their exposure.



6. TEST RESULTS

H-Field Measurements

Note : peak measurements were performed. RMS values were calculated from the peak measurement. Please refer to the formula for calculating the RMS value: [Field Strength * \/Duty Cycle]

6.1.1 H field Measurement Results

H-Field TEST results of DUT to phone test Configuration 1 &2 [Phone to Phone]

FCC RF Exposure Result					
Test Configuration	Test mode	Test distance	Test Position	H-Field Limit (A/m)	H-Field meas data (A/m)
		20 cm	Тор		0.137
			Bottom		0.121
	Operation Real Product		Edge 1	1.62	0.126
	(Power <10% charging)	15 cm	Edge 2	1.63	0.126
			Edge 3		0.129
			Edge 4		0.131
		20 cm	Тор		0.136
			Bottom		0.121
Configuration 1	Operation Real Product		Edge 1	1.63	0.121
Configuration	(Power 50~55% charging)	15 cm	Edge 2	1.05	0.126
			Edge 3		0.129
			Edge 4		0.131
		20 cm	Тор		0.136
			Bottom		0.120
	Operation Real Product		Edge 1	1.63	0.125
	(Power 90~95% charging)	15 cm	Edge 2	1.03	0.124
			Edge 3		0.128
			Edge 4		0.130
Configuration 2	Operation Real Product	20 cm	Тор	1.63	0.135
Computation 2	(Power <10% charging)	20 011		1.05	



FCC RF Exposure Result					
Test Configuration	Test mode	Test distance	Test Position	H-Field Limit (A/m)	H-Field meas data (A/m)
		20 cm	Тор		0.151
			Bottom		0.136
	Operation Real Product		Edge 1	1.63	0.129
	(Power <10% charging)	15 cm	Edge 2		0.130
			Edge 3		0.129
			Edge 4		0.134
		20 cm	Тор		0.150
Configuration 3	Operation Real Product		Bottom		0.134
			Edge 1	1.63	0.127
	(Power 50~55% charging)	15 cm	Edge 2		0.130
			Edge 3		0.128
			Edge 4		0.134
		20 cm	Тор		0.149
			Bottom		0.134
	Operation Real Product		Edge 1	1.63	0.126
	(Power 90~95% charging)	15 cm	Edge 2	1.03	0.129
			Edge 3		0.128
			Edge 4		0.133
Configuration 4	Operation Real Product (Power <10% charging)	20 cm	Тор	1.63	0.150

H-Field TEST results of DUT to phone test Configuration 3 &4[Phone to phone]



FCC RF Exposure Result					
Test Configuration	Test mode	Test distance	Test Position	H-Field Limit (A/m)	H-Field meas data (A/m)
Configuration 5	Operation Real Product (Power <10% charging)	20 cm	Тор	-	0.152
			Edge 1		0.126
		15 cm	Edge 2 1.63 Edge 3	1.63	0.128
		15 cm		-	0.127
			Edge 4		0.132
	Operation Real Product (Power 50~55% charging)	20 cm	Тор	1.63	0.134
			Edge 1		0.125
		15 am	Edge 2		0.128
		15 cm Edge 3 Edge 4	Edge 3		0.126
			Edge 4		0.131
	Operation Real Product (Power 90~95% charging)	20 cm	Тор		0.132
			Edge 1		0.124
		45	Edge 2		0.128
		15 cm	Edge 3		0.125
			Edge 4		0.131
Configuration 6	Operation Real Product (Power <10% charging)	20 cm	Тор	1.63	0.134

H-Field TEST results of DUT to phone test Configuration 5 &6[Watch]



FCC RF Exposure Result					
Test Configuration	Test mode	Test distance	Test Position	H-Field Limit (A/m)	H-Field meas data (A/m)
	Operation Real Product (Power <10% charging)	20 cm	Тор	1.63	0.133
			Edge 1		0.118
		15 cm	Edge 2 1.63 Edge 3 Edge 4		0.123
		15 Cm			0.119
Configuration 7					0.126
	Operation Real Product (Power 50~55% charging)	20 cm	Тор		0.132
		Edge 1	Edge 1		0.118
		15 cm	Edge 2 1.63 Edge 3	1.63	0.122
		15 Cm		0.119	
			Edge 4		0.124
	Operation Real Product (Power 90~95% charging)	20 cm	Тор		0.132
		Edge 1		0.117	
		15 cm	Edge 2	1.63	0.122
			Edge 3]	0.118
			Edge 4		0.123
Configuration 8	Operation Real Product (Power <10% charging)	20 cm	Тор	1.63	0.132

H-Field TEST results of DUT to phone test Configuration 7 &8[EarBuds]



H-Field TEST results of DUT to phone test Configuration 5

Results of H-Field Measurement (A/m) at the Worst case configuration				
The Distance from the device to the center of the	H-Field Meas. (A/m)			
measurement probe (cm)				
0 (3 cm)	12.235			
2 (5 cm)	3.690			
4 (7 cm)	1.118			
6 (9 cm)	0.464			
8 (11 cm)	0.263			
10 (13 cm)	0.204			
12 (15 cm)	0.193			
14 (17 cm)	0.185			
16 (19 cm)	0.177			
18 (21 cm)	0.165			
20 (23 cm)	0.155			

*The contact distance between the device and the probe is 3cm from the center of the probe.



7. Conclusion

	H-Field (A/m)
MPE Limit	1.63
Maximum Measurement Result	0.152
Percentage (%)	9.3

H-Field test result was less than 50% of MPE Limit